



DOCUMENT CHANGE REQUEST

DCR number 1375 Changes required for: General

Date: 2021/02/18

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Status: IMPLEMENTED

Originator: Steve Thacker

Organisation: ESCC Executive
Secretariat

Title: Generic Specification for Discrete Semiconductor Components

Number: 5000

Issue: 9

Other documents affected:

Page:

29, 41, 42

Paragraph:

new 8.25, Chart F4A

Original wording:

See ESCC 5000 issue 9

Proposed wording:

Test requirements for Internal Gas Analysis is added for SPQ as follows; see attached mark-up specification ESCC5000 Draft 10 for details:

1) Add new Para. 8.25 as follows:

"8.25 INTERNAL GAS ANALYSIS
MIL-STD-883, Test Method 1018."

2) In Chart F4A, add Internal Gas Analysis as the first test in the Assembly Capability Subgroup with applicable new note 6 as follows. The original note 6 is deleted.

"6. Only applicable to the qualification testing phase for single phase qualification (SPQ)."

Justification:

As required by PSWG & ESA review of IGA within ESCC 5000 (based around the same test already included in ESCC9000)

Attachments:

esc5000_draft10a_in_review.docx

Modifications:

N/A

Approval signature:



Date signed:

2021-02-18